Search Notes				

Application/Control N	0.

09/742,171

2825

Examiner

A. M. Thompson

Applicant(s)/Patent under Reexamination
TEIG ET AL.
Art Unit

SEARCHED			
Class	Subclass	Date	Examiner
716	7	8/1/2005	AMT
716	9	8/1/2005	AMT
716	10	8/1/2005	AMT
			,

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH N (INCLUDING SEAR	NOTES CH STRATEGY	')
	DATE	EXMR
IEEE; USPAT; USPGPUB	8/1/2005	АМТ